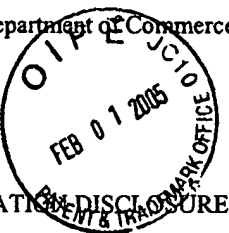



U.S. Department of Commerce, Patent and Trademark Office  INFORMATIONAL DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	Application No.:	10/748,827
	Filing Date:	December 29, 2003
	First Named Inventor:	Joonhyung Kwon
	Group Art Unit:	2856
	Examiner Name:	Larkin, Daniel Sean
	Confirmation No.:	7166
	Attorney Docket No.:	PSI004-1C US

U.S. Patent Documents							
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
		US 5,672,816	09/1997	Park et al.	73	105	
<i>DM</i>		US 3,600,811	08/1971	Weyrauch, Adolf	33	<del>707</del>	
Foreign Patent Documents							
							Translation
		Document	Date	Country	Class	Subclass	Yes No
Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)							
<i>DM</i>	AQ	Binnig G., et al, "Atomic Force Microscope", Physical Review Letters, vol 56, No. 9, Mar. 3, 1986 pp. 930-933.					
	AR	Hansma, P.K., et al, "A new optical-lever based atomic force microscope", J. Appl. Phys., 76(2) Jul. 15, 1994, American Institute of Physics, pp. 796-799.					
	AS	Meyer, Gerhard et al, "Erratum: Novel optical approach to atomic force microscopy", Appl. Phys. Lett. 53(24), Dec. 12, 1988, American Institute of Physics, pp. 2400-2402.					
	AT	"Dimensions 3100 Scanning Probe Microscope The Most Versatile SPM Ever Manufactured", www.di.com/Products/Dim/3100/D3100Main.html, Digital Instruments, Veeco Metrology Group © 1998-2001, print date Dec. 17, 2001, 4 pages.					
	AY	"Dimension 3100 Scan Techniques Unparalleled Power and Versatility", www.di.com/Products/Dim/3000/D31.scantechniques.html, Digital Instruments Veeco Metrology Group, ©1998-2001, print date Dec. 17, 2001, 2 pages.					
	AZ	AutoProbe M5™ Scanning Probe Microscope, Microscopes Veeco Metrology Group, 2001© TM Microscopes, Veeco, 4 pages.					
	BA	"TappingMode Imaging: Application and Technology", www.di.com/AppNotes/TapMode/TapModeMain.html, Digital Instruments, Veeco Metrology Group, ©1995-2001, Digital Instruments, print date Dec. 17, 2001, 5 pages.					
<i>DM</i>	BB	"NanoScope Vertical Engage Scanner", www.di.com/Products/Mult/JVScanner.html, Digital Instruments Veeco Metrology Group, ©1996-2001, Digital Instruments, print date Dec. 17, 2001, 1 page.					

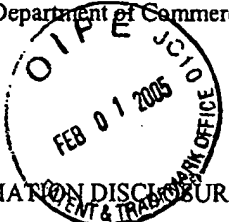
Examiner: <i>[Signature]</i>	Date Considered: <i>25 April 2005</i>
* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.	

\* The Park et al. reference was previously considered in the IDS filed 29 December 2003.

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U.S. Patent Documents								
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
<i>Dr</i>		US 5,666,051	09/1997	Junker et al.	<del>324</del>	<del>209</del>		
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)								
<i>Dr</i>	BC	"NanoScope MultiMode Scanning Probe Microscope", www.di.com/products/Multi/MMAIone.html, Digital Instruments Veeco Metrology Group, © 1996-2001, Digital Instruments, 8 page.						
	BD	"NanoScope ® MultiMode™ SPM The World's Highest Resolution SPM", www.di.com/Products/Multi/MMMain.html, Digital Instruments Veeco Metrology Group, ©1995-2001, Digital Instruments, print date Dec. 17, 2001 7 pages.						
	BE	"Products", Digital Instruments, Veeco Metrology Group Products, www.di.com/products2/products_all.html, print date Dec. 17, 2001, 5 pages.						
	BF	"AutoProbe CP Research The Most Flexible Research SPM", www.theermomicro.com/products/cp.htm, Microscopes Veeco Metrology Group, ©2001, print date Dec, 17, 2001, 2 pages.						
	BG	Manalis, S. R., et al, "High-speed atomic force microscopy using an integrated actuator and optical lever detection", Rev. Sci. Instrum. 67(9), Sep. 1996, pp. 3294-3297.						
	BH	"Microlevers™ General Purpose Cantilevers", Park Scientific Instruments © 1998, 1 page.						
	BI	Babcock, K.L. et al. "Phase Imaging: Beyond Topography", Digital Instruments, 3 pages, published prior to Feb. 15, 2002						
	BJ	"AutoProbe CP Research AP 2001", ThermoMicroscopes, 5 pages, published prior to Feb. 15, 2002						
<i>Dr</i>	BK	"AutoProbe CP Research Scanning Probe Microscope", ThermoMicroscopes, 4 pages, published prior to Feb. 15, 2002						

Examiner: <i>Dr. L. Z.</i>	Date Considered: <i>25 April 2005</i>
* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.	

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U.S. Patent Documents								
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
<i>DL</i>		US 2001/0029674	10/2001	Cutler, Donald R.	<del>33</del>	<del>1.00M</del>		
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)								
<i>DL</i>	BL	"AutoProbe MSE AP-5001", ThermoMicroscopes, 4 pages, published prior to Feb. 15, 2002						
<i>DL</i>	BM	"The Dimension <sup>TM</sup> 5000 Scanning Probe Microscope", Digital Instruments, 8 pages, published prior to Feb. 15, 2002						
<i>DL</i>	BN	"The Dimension <sup>TM</sup> 3000 Scanning Probe Microscope", Digital Instruments, 6 pages, published prior to Feb. 15, 2002						
<i>DL</i>	BO	"The Dimension <sup>TM</sup> 3100 Scanning Probe Microscope", Digital Instruments, 1 page, published prior to Feb. 15, 2002						

Examiner: <i>DL</i>	Date Considered: <i>25 April 2005</i>
* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.	